## Application/Control No. Applicant(s)/Patent Under Reexamination 10/615,404 ONOE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 TAN X. DINH 2627 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 06-2006 US-7,065,033 B2 Onoe et al. 369/126 Α US-2004/0042351 A1 03-2004 В Onoe et al. 369/13.01 US-2003/0053400 A1 03-2003 C Cho et al. 369/126 US-D US-Ε US-F

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